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Title of Invention TEST APPARATUS FOR TESTING A SEMICONDUCTOR DEVICE, AND METHOD FOR TESTING THE SEMICONDUCTOR DEVICE (as amended)												
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Applicant 1												
Applicant Authority • Inventor												
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Maxhu	ette-Haid	hof	Coun	try Of Re	esiden	cei	DE					
Citizenship under 37 CFR 1.41(b) DE												
g Addr	ess of A	pplicant:	l									
Address 1 Bergmannstr. 57												
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City Maxhuette-Haidhof State/Province												
Postal Code 93142					Cour	ntryi	DE		<b>'</b>			
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TEST APPARATUS FOR TESTING A SEMICONDUCTOR DEVICE, AND METHOD FOR TESTING I SEMICONDUCTOR DEVICE (as amended)

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Application Da	nta Sheet 37 CFR 1.76	Attorney Docket Number	I431.172.101/FIN574PCT/US
Application bata offect of CTR 1.70		Application Number	
Title of Invention	TEST APPARATUS FOR TE SEMICONDUCTOR DEVICE		PEVICE, AND METHOD FOR TESTING THE

# **Application Information:**

Title of the Invention	itle of the Invention TEST APPARATUS FOR TESTING A SEMICONDUCTOR DEVICE, AND METHOD FOR TESTING THE SEMICONDUCTOR DEVICE (as amended)					
Attorney Docket Number	Number I431.172.101/FIN574PCT/US Small Entity Status Claimed					
Application Type	Application Type Nonprovisional					
Subject Matter Utility						
Suggested Class (if any)  Sub Class (if any)						
Suggested Technology Center (if any)						
Total Number of Drawing Sheets (if any)  Suggested Figure for Publication (if any)						
Publication Information:						
Request Early Publication (Fee required at time of Request 37 CFR 1.219)						
and certify that the inv	Request Not to Publish. I hereby request that the attached application not be published under 35 U.S.C. 122(b) and certify that the invention disclosed in the attached application has not been and will not be the subject of an application filed in another country, or under a multilateral agreement, that requires publication at eighteen months					

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Customer Number	25281		

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This section allows for the applicant to claim benefit under 35 U.S.C. 119(e), 120, 121, or 365(c). Providing this information in the application data sheet constitutes the specific reference required by 35 U.S.C. 119(e) or 120, and 37 CFR 1.78(a)(2) or CFR 1.78(a) (4), and need not otherwise be made part of the specification.

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Prior Application Status			Remove				
Application Number	Continuity Type	Prior Application Number	Filing Date (YYYY-MM-DD)				
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# **Foreign Priority Information:**

This section allows for the applicant to claim benefit of foreign priority and to identify any prior foreign application for which priority is not claimed. Providing this information in the application data sheet constitutes the claim for priority as required by 35 U.S.C. 119(b) and 37 CFR 1.55(a).

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Application Number  Title of Invention TEST APPARATUS FOR TESTING A SEMICONDUCTOR DEVICE, AND METHOD FOR TESTING TH	Application Da	ta Sheet 37 CFR 1.76	Attorney Docket Number	I431.172.101/FIN574PCT/US
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Application Number	Country i	Parent Filing Date (YYYY-MM-DD)	Priority Claimed				
10 2004 007 696.0	DE	2004-02-16	● Yes ○ No				
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Application Number	Country <sup>i</sup>	Parent Filing Date (YYYY-MM-DD)	Priority Claimed				
PCT/DE2005/000216	EP	2005-02-09	● Yes ○ No				
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#### **Assignee Information:**

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Assignee 1				Remove			
If the Assignee is an Organization	ganization check here.	<b>√</b>					
Organization Name	Infineon Technologies AG						
Mailing Address Information:							
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Address 2							
City	Munich		State/Province				
Country i DE			Postal Code	81669			
Phone Number			Fax Number				
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### Signature:

_	A signature of the applicant or representative is required in accordance with 37 CFR 1.33 and 10.18. Please see 37 CFR 1.4(d) for the form of the signature.							
Signature	/Steven E. Dicke/			Date (YYYY-MM-DD)	2006-08-16			
First Name	Steven E.	Last Name	Dicke	Registration Number	38431			

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